

# TEST/CALIBRATION REPORT

# EMC / EMI Test Report for MECO Analog Frequency Meter

Testing as per EN 50082-2 (Edition 1995)

DEPARTMENT OF ELECTRONICS, (STQC Dte.)

Government of India.

Plot F 7/8, M. I. D. C. Area, Opp. Seepz, Andheri (E), Mumbai - 400 093.

#### MEMORANDUM

The Test/Calibration Report issued by ERTL (W) is a record of the measurements conducted on the products submitted to it for testing / calibration and the results thereof. Unless otherwise specified in the report, the results are applicable only to those products which have been tested/calibrated and do not apply to other products even though declared to be identical.

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### LIABILITY CLAUSE

- ERTL (W) shall not be liable for any change in test / calibration data and performance specification on account of malfunctioning of the standard/ instrument/equipment due to any damage caused to it after the report, in respect of it, has been issued.
- 2. The report shall not be regarded in any way diminishing the normal contractual responsibilities/obligations between the customer and ERTL (W).
- 3. The results reported in this report are valid only at the time of and under the stated conditions of the measurements.

ELECTRONICS REGIONAL TEST LABORATORY (WEST)  DEPARTMENT OF ELECTRONICS (STQC Dtc.)	REPORT NO.: ERTL(W)/98EMI00088		
SUBJECT : TESTING OF ANALOGUE FREQUENCY METER	24TEAUG 1998 PAGE OF 6		

**SCOPE** 1.

1.1 Service Request No.

ERTL(W)/9801029 dtd. 17/8/98

Service Request finalised on : 1.1.1

17-AUG-88

1.2 Requested by

(Name and address of organisation)

MECO INSTRUMENTS P. LTD.7

T.J. ROAD? SEWRI? MUMBAI - 400 015.

**Description** 1.3 Item

Manufacturer and Type No. **Qty** 

Serial Nos.

No.

1. Analogue Frequency Meter 01 M/s Meco Instruments Pvt. Ltd. Not Marked

Model No.: F 72

1.4 Test specifications EN 50082-2,1995 ed.

1.5 Lab Ambient Temperature: 25 °C

Humidity

: 57 % RH

1.6 Test Equipment used : 1) EMI/004 : Static Discharge Simulator

2) EMI/033 : EFT Simulator

3) EMI/034 : G-Strip Immunity Chamber

4) EMI/036 : Signal Generator

5) EMI/037: RF Amplifier



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## 2.0 Test Results:

Sr.	Test	Test Condition	Requirement	Observations	Remarks
No	Parameter				
2.1	Electrostatic	As per EN 50082-	Performance	The display pointer	Complied
	Discharge	2,1995	criterion 'B'*	was found to be	
			-	fluctuating between	
		Amplitude :		50 Hz and 60 Hz	
		Air	·	which was self	1
		Discharge: 8KV	•	recoverable after	1
		0		removal of the	
	İ	Contact	·	discharge.	
1		Discharge: 4KV			
		Polarity:			
		Positive and			
		Negative			
		EUT Supply:			
		360 - 440 V, 50 Hz			

<sup>\*</sup> For performance criteria please refer Annexure 'A'



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Test Parameter	Test Condition	Requirement	Observations	Remarks
Radiated Immunity	As per EN 50082-2,1995  Freq. Range: 80 - 1000MHz  Amplitude:10V/m  Modulation:80% A.M. at 1KHz  EUT Supply: 360 - 440 V, 50	Performance Criterion 'A'*	Fluctuations in the display pointer was observed to be ±0.5 Hz.	Complied
	Parameter Radiated	Parameter  Radiated Immunity  As per EN 50082- 2,1995  Freq. Range: 80 - 1000MHz  Amplitude:10V/m  Modulation:80% A.M. at 1KHz  EUT Supply:	Radiated Immunity  As per EN 50082- 2,1995  Freq. Range: 80 - 1000MHz  Amplitude:10V/m  Modulation:80% A.M. at 1KHz  EUT Supply: 360 - 440 V, 50	Radiated As per EN 50082- Performance Criterion 'A'*  Freq. Range: 80 - 1000MHz  Amplitude: 10V/m  Modulation: 80% A.M. at 1KHz  EUT Supply: 360 - 440 V, 50

<sup>\*</sup> For performance criteria please refer Annexure 'A'



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Sr.	Test	Test Condition	Requirement	Observations	Remarks
No	Parameter				
2.3	Electrical Fast Transients	As per EN 50082-2, 1995  Amplitude: Common Mode: 2KV  Polarity: Positive and Negative  Pulse repetition	Performance criterion 'B'*	The display pointer was found to be fluctuating by ±0.5Hz which was self recoverable after removal of EFT.	Complied
		Frequency:5KHz  EUT Supply: 360 - 440 V, 50 Hz			

<sup>\*</sup> For performance criteria please refer Annexure 'A'



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3.0 General Remarks: Nil

	क्रिय वर्गका क्रिय
REPORT APPROVED BY	REPORT REALEASED BY
HEAD (EMI/EMC)	OIC (CSC)

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#### Annexure 'A'

### Performance Criteria as per European Norms.

Performance Criteria 'A': The EUT shall continue to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the EUT is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible loss is not specified by the manufacture then either of these may be derived from the product description and documentation and what the user may reasonably expect from the EUT if used as intended.

Performance Criteria 'B': The EUT shall continue to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the EUT is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed. No change of actual operating state or stored data is allowed. If the minimum performance level or the permissible loss is not specified by the manufacture then either of these may be derived from the product description and documentation and what the user may reasonably expect from the EUT if used as intended.



# **OUR ACCREDITATION STATUS**

- ERTL (West) set up under the STQC Directorate, Dept. of Electronic, Govt. of India has been accreditated under number of national / international systems.
- ERTL test reports have a wide acceptance in Govt. Departments, Private and Public Sector units in India.
- Besides, ERTL also have following accreditations.

SYSTEM	AREA	CTATUC
STSTEM	ANEA	STATUS
IECQ, Geneva (International Electrotechnical Commission System for Component Qualification Approval)	Component Testing  * Resistors (Fixed)  * Capacitors (Fixed)	Accreditated as ITL (Independent Test Laboratory)
NABL (C), India [National Accreditation Board for Test & Calibration Laboratories (Calibration System)]	Calibration  * Electronic Measurements  * Electrical Measurements	Accreditated as Echelon II level Calibration Laboratory
NABL (T), India	Components & Equipments	Recommended for Accreditation
[National Accreditation Board for Test & Calibration Laboratories (Testing System)]		
UL, U.S.A. (Underwriters Laboratory)	Safety Testing of  * Information Technology Products  * Audio Video Products.  * Picture Tubes  * H. V. Products	Facilities Approved
UL, I.I.S.	Follow-up Services Inspection in Electrical Product (s)	International Inspection Centre - 512
IECEE - CB Scheme	* Information Technology Products  * Mains Operated Electronic Consumer Products  * Safety critical components such as Switches Cables	Approved as a CB test Laboratory
	Fuses Capacitors	